

Testing Summary Samsung Active II Tablet Dual USB Docking Station

(7160-1368)

Summary of Tests Performed at Gamber-Johnson

Julillary of Tests Ferformed at Gamber-Johnson		
Test Description	Test Parameters	
Vibration –	MIL-STD-810G, Method 514.6, Procedure 1, Category 4, per Figure	
Operational	514.6C-1. Test duration is one hour along three mutually orthogonal	
Test date: May, 2019	axes – not simultaneously (3 hours total).	
	Unit is unlocked	
Vibration –	MIL-STD-810G, Method 514.6, Category 24, per Figure 514.6E-1. Test	
Non-Operational	duration is one hour along three mutually orthogonal axes – not	
(Minimum Integrity)	simultaneously.	
Test date: April, 2019	Unit is unlocked	
Functional Shock -	MIL-STD-810G, Method 516.6, Procedure 1, 3 positive and 3 negative	
Non-Operational	pulses each axis (vertical, longitudinal and transverse), 18 pulses	
Test date: April, 2019	20G, 11ms half sine	
	Unit is unlocked	
Mechanical Shock	MIL-STD-810G, Method 516.6, Procedure 1, 3 positive and 3 negative	
Safety -	pulses each axis (vertical, longitudinal and transverse), 18 pulses	
Non-Operational	40G, 11ms half sine	
Test date: April, 2019	Unit is unlocked	
Electrostatic	ISO 10605, Section 8, Table C.2, Category 2 – Direct Air Discharge	
Discharge –		
Operational		
Test date: April 2019		
Cycle Testing –	30,000 cycles of the docking connector, latching and locking	
Non-Operational	mechanisms	
Test date: Dec., 2017		

Summary of Tests Performed at Independent Facility

Test Description	Test Parameters
Humidity	MIL-STD 810G, Method 507.5, Procedure II, Aggravated, Table 507.5-
Test date: April 2019	
	 Ten 24-hour cycles, temperature varied from 30°C to 60°C to
	30°C at constant 95% relative humidity.
Low Temperature:	MIL-STD 810G, Method 502.5, Procedure II
Operational	 -20°C Operating, 24-hour duration
Test date: April 2019	

An ISO 9001:2015 certified company

Gamber-Johnson LLC · 3001 Borham Avenue · Stevens Point, Wisconsin 54481 PHONE: 1-715-344-3790 · FAX: 1-715-344-5209 · EMAIL: gamberj@gamberjohnson.com · www.gamberjohnson.com



Low Temperature:	MIL-STD 810G, Method 502.5, Procedure I
Storage	 -40°C Non-Operating, 24-hour duration
Test date: April 2019	
High Temperature:	MIL-STD 810G, Method 501.5, Procedure II, Table 501.5-II, Induced
Operational	Conditions
Test date: April 2019	 Five 24-hour cycles, temperature varied from 30°C to 60°C to
	30°C
High Temperature:	MIL-STD 810G, Method 501.5, Procedure I, Table 501.5-III, Induced
Storage	Conditions
Test date April, 2019	 Seven 24-hour cycles, temperature varied from 33°C to 71°C
	to 33°C
Shock – Crash Hazard	SAE J1455, Section 4.11.3.5, per Figure 13
Test date: 6/4/2019	Unit is unlocked
EMC Testing	EN 55032:2015
Test date: April 2019	CISPR 32 – Class B
	 FCC Part 15, Subpart B – Class B
EMC Testing	EN 50498:2010
Test date: April 2019	
EMC Testing (E Mark)	UN ECE R10:219 Addendum 9, Revision 6
Testing	• CISPR 25:2002
Test Date: June 2020	• ISO 7637-2:2004
	• ISO 11452-2:2004
Safety Testing	UNECE 118R Annex 10
Test Date: April 2021	

Other Certifications

Description
EN 50581:2012 RoHS2 Directive 2011/65/EU